

Search Notes

Application/Control No.

09/886,255

Examiner

Jacob Meek

Applicant(s)/Patent under
Reexamination

DENNO, SATOSHI

Art Unit

2637

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---------------------------|-----------|----------|
| 375 | 235,343 349,345 344 | 6/22/2005 | JM |
| 329 | 304,318 | 6/22/2005 | JM |
| 329 | 341 | 6/22/2005 | JM |
| 455 | 324,305 | 6/22/2005 | JM |
| 455 | 239.1,337 | 6/22/2005 | JM |
| 455 | 245.1,303 | 6/22/2005 | JM |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 375 | 316 | 6/22/2005 | JM |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|------|-----------|------|
| East | 6/22/2005 | JM |
| NPL | 6/22/2005 | JM |
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